

**MSE 582 - Introduction to
transmission electron
microscopy**

&

**MSE 640 - Transmission
electron microscopy &
crystalline imperfections**

Instructor: Eric Stach

Goals

- **Goals:**

- **MSE 582: Perform simple imaging and diffraction experiments with the microscope**
- **MSE 640:**
 - **In depth understanding of fundamentals of scattering, diffraction and imaging**
 - **Practical application of these concepts towards materials characterization**

- **Taught in four units:**

- **Operation of the TEM (MSE 582 content)**
- **Diffraction**
- **Imaging**
- **Spectroscopy**

About me ...

Education

- B.S.E. - Duke University
- M.S.M.S.E. - University of Washington
- Ph.D. - University of Virginia

Professional Experience

- Graduate research - IBM Watson Research Labs
- Staff Scientist, Principal Investigator and Program Leader, National Center for Electron Microscopy & Materials Sciences Division, Lawrence Berkeley National Laboratory
- Associate Prof @ Purdue since January 2005

Research expertise

- Crystalline defects, crystal growth, electronic thin films, electron microscopy, mechanical behavior, nanostructured materials

Course mechanics

MSE 582: Pass/Fail

- Can you take a picture with the microscope?

MSE 640:

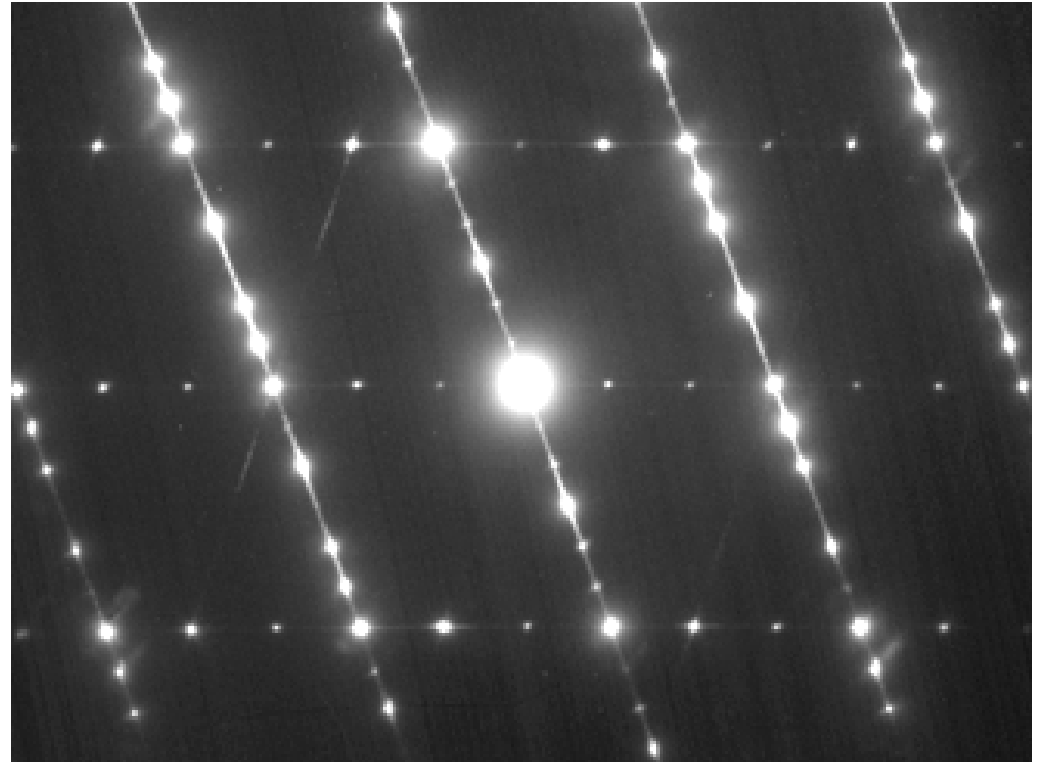
- Homework (20%)
- Laboratories (30%)
 - We'll engage in a systematic study of the microstructure of an advanced aluminum alloy
- Exams (50%)
 - Midterm (after diffraction unit - 20%) and a Final (30%)

What can you do with a TEM?

What can you do with a TEM?

Selected Area Diffraction (SAD)

- Crystallographic structure from particular areas of a sample.
- Used to distinguish and identify crystalline (and amorphous) phases in a material.



Selected area diffraction pattern

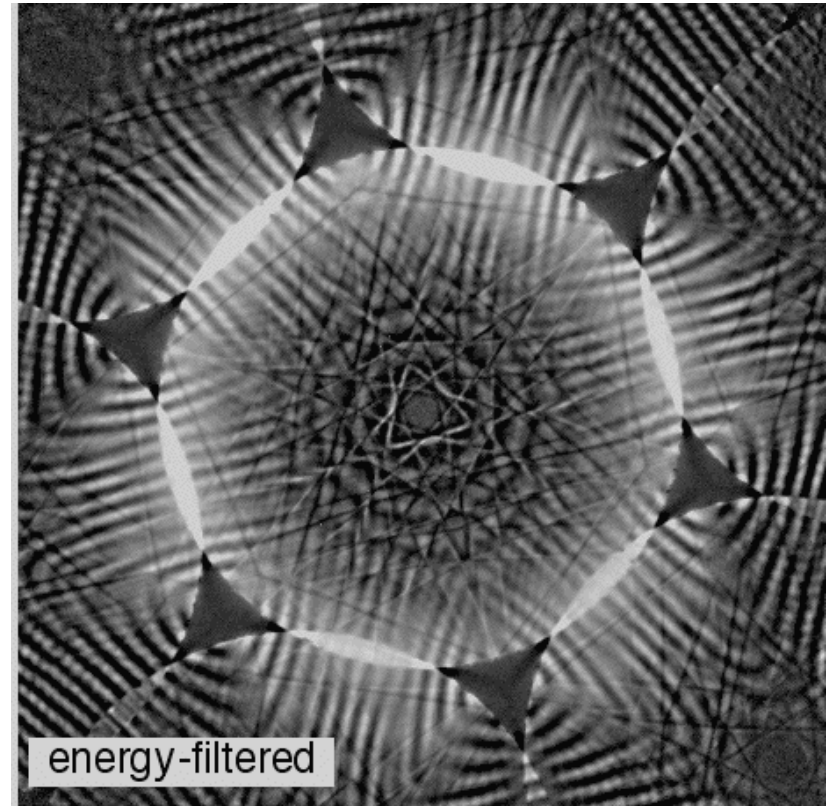
$10\bar{1}0$ Zone axis pattern of a hexagonal GaN / cubic GaN heterostructure

Pattern reveals extensive twinning in the cubic layer

What can you do with a TEM?

Convergent Beam Electron Diffraction (CBED)

- Point and Space Group determination
- Local strain
- Nanoscale diffraction



Convergent beam electron diffraction pattern

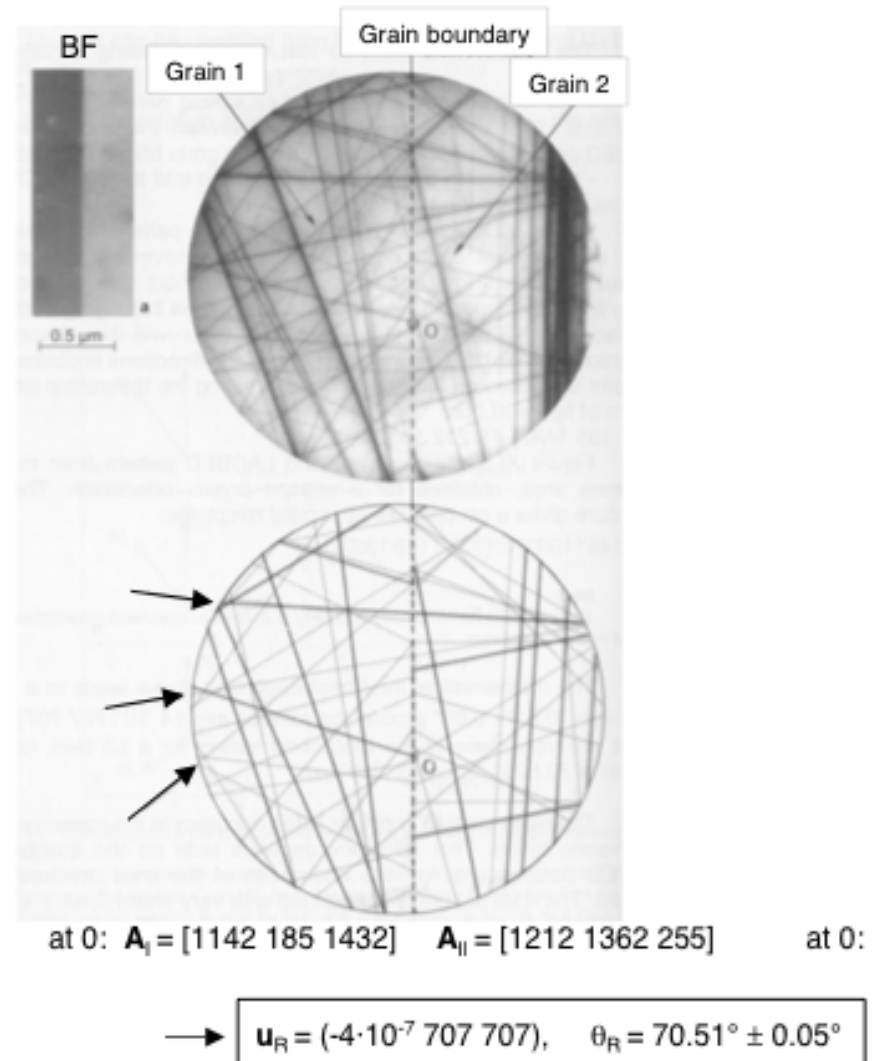
111 zone axis pattern of silicon

Note detailed structure in the central disk

What can you do with a TEM?

Large-angle Convergent Beam Electron Diffraction (LACBED)

- Misorientation across grain boundaries
- Dislocation Burgers vector
- Crystalline symmetry



What can you do with a TEM?

Diffraction Contrast Imaging

Strain fields

- Dislocations
- Stacking faults
- Grain boundaries
- Precipitates
- Second phases



Typical bright field image

Dislocation configurations at the interface between a SiGe heteroepitaxial layer and a Si (100) substrate viewed in plan view (along [100])

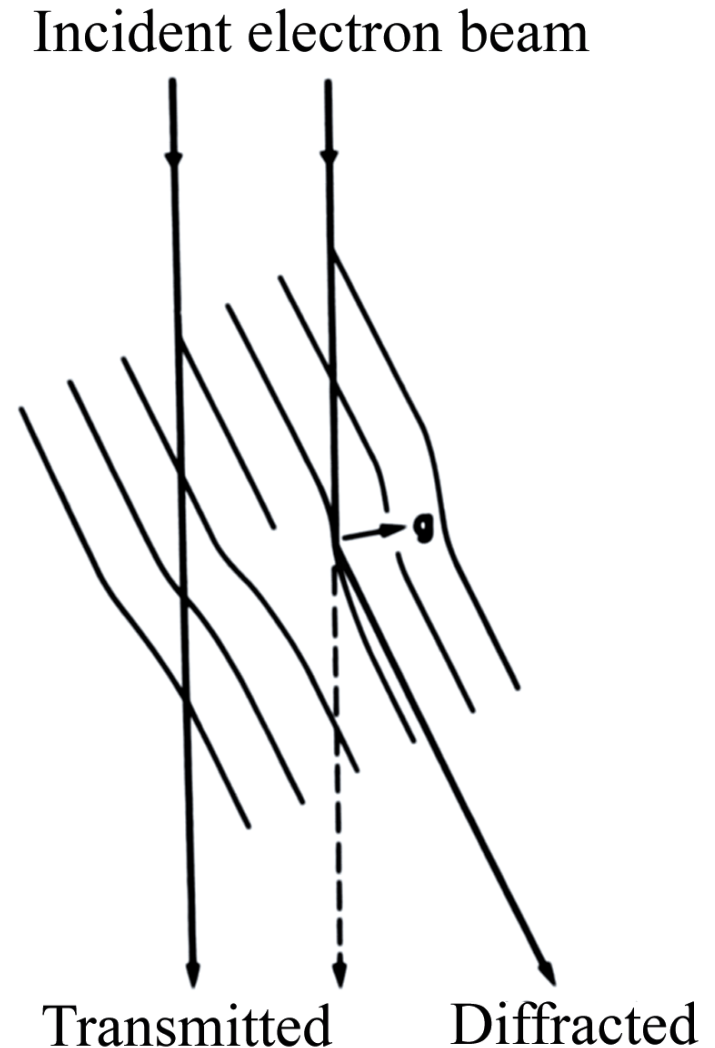
What can you do with a TEM?

Diffraction Contrast

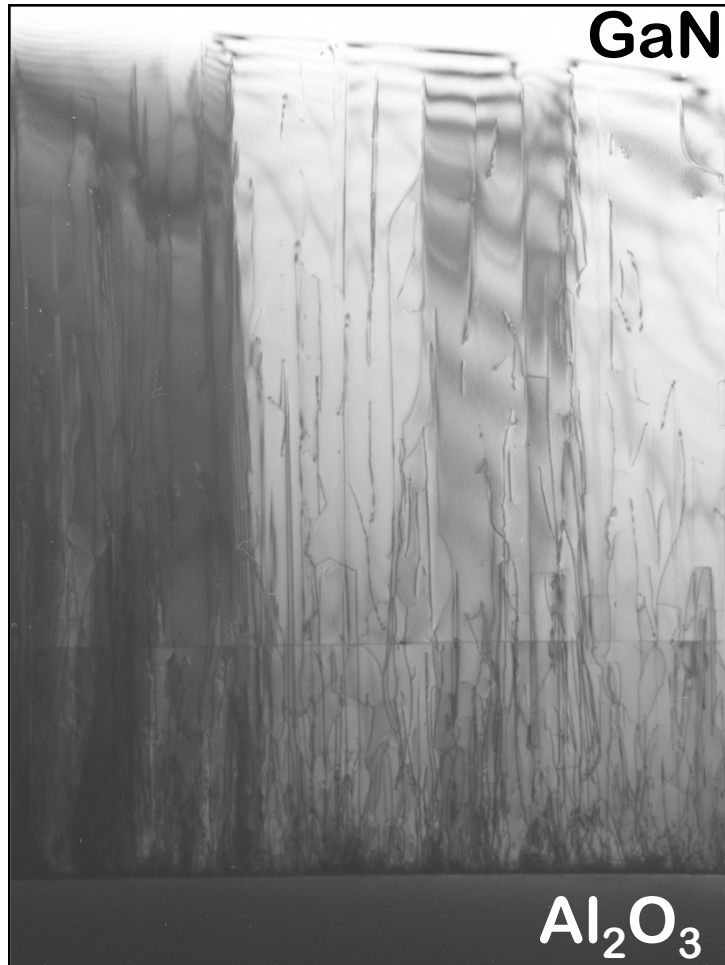
Imaging

One beam selected for imaging

- Transmitted - “bright field”
- Diffracted - “dark field”



What can you do with a TEM?



Bright field image



Dark field image

What can you do with a TEM?



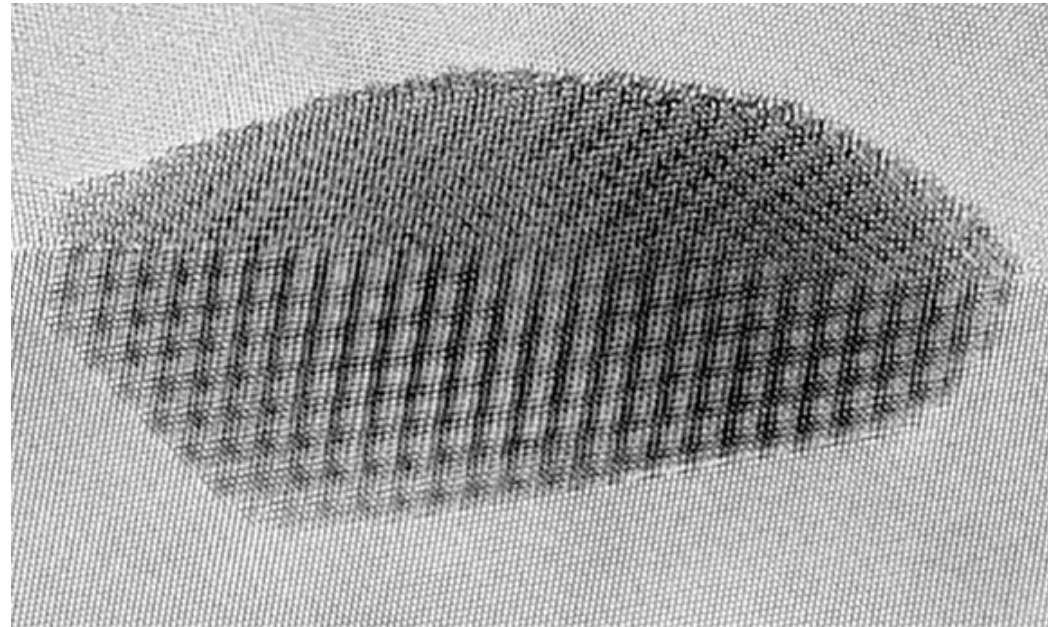
'Weak beam' dark field image

What can you do with a TEM?

**High-resolution
imaging**

**Atomic column
images at
resolutions from
0.7Å and above**

- Interference of
transmitted and
diffracted electron
waves**

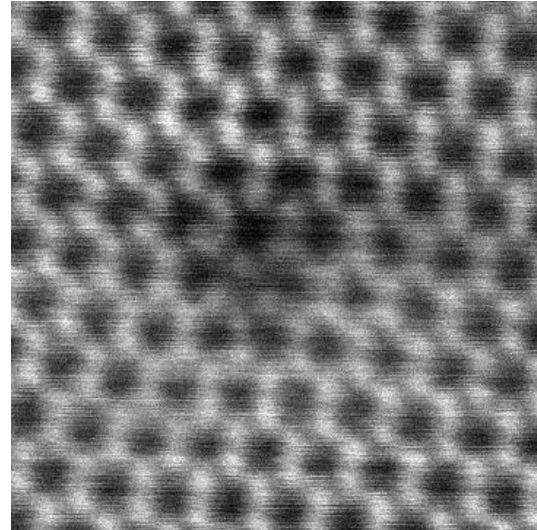


High resolution micrograph of a precipitate at a high angle grain boundary in aluminum

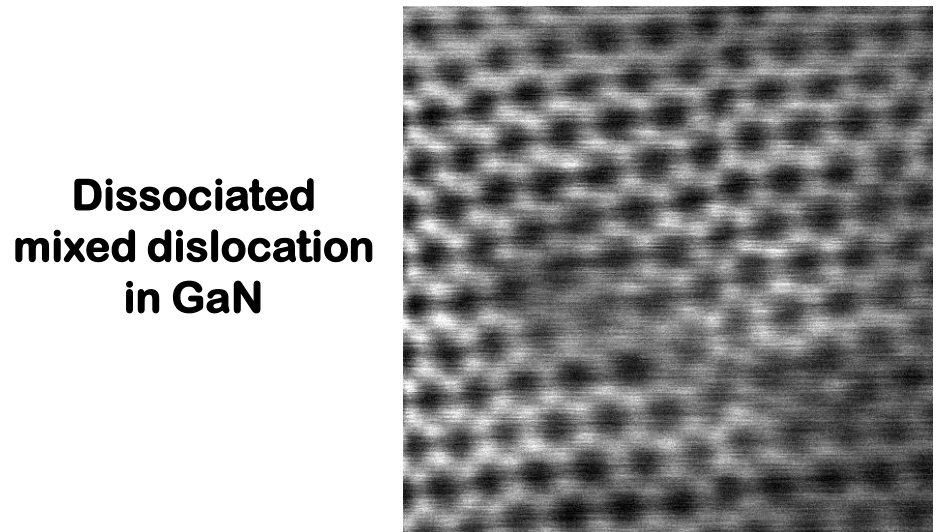
What can you do with a TEM?

High angle annular dark field (HAADF) imaging

- Accomplished in a dedicated Scanning TEM (STEM)
- Collects incoherent scatter, yields atomic resolution



Mixed dislocation in GaN

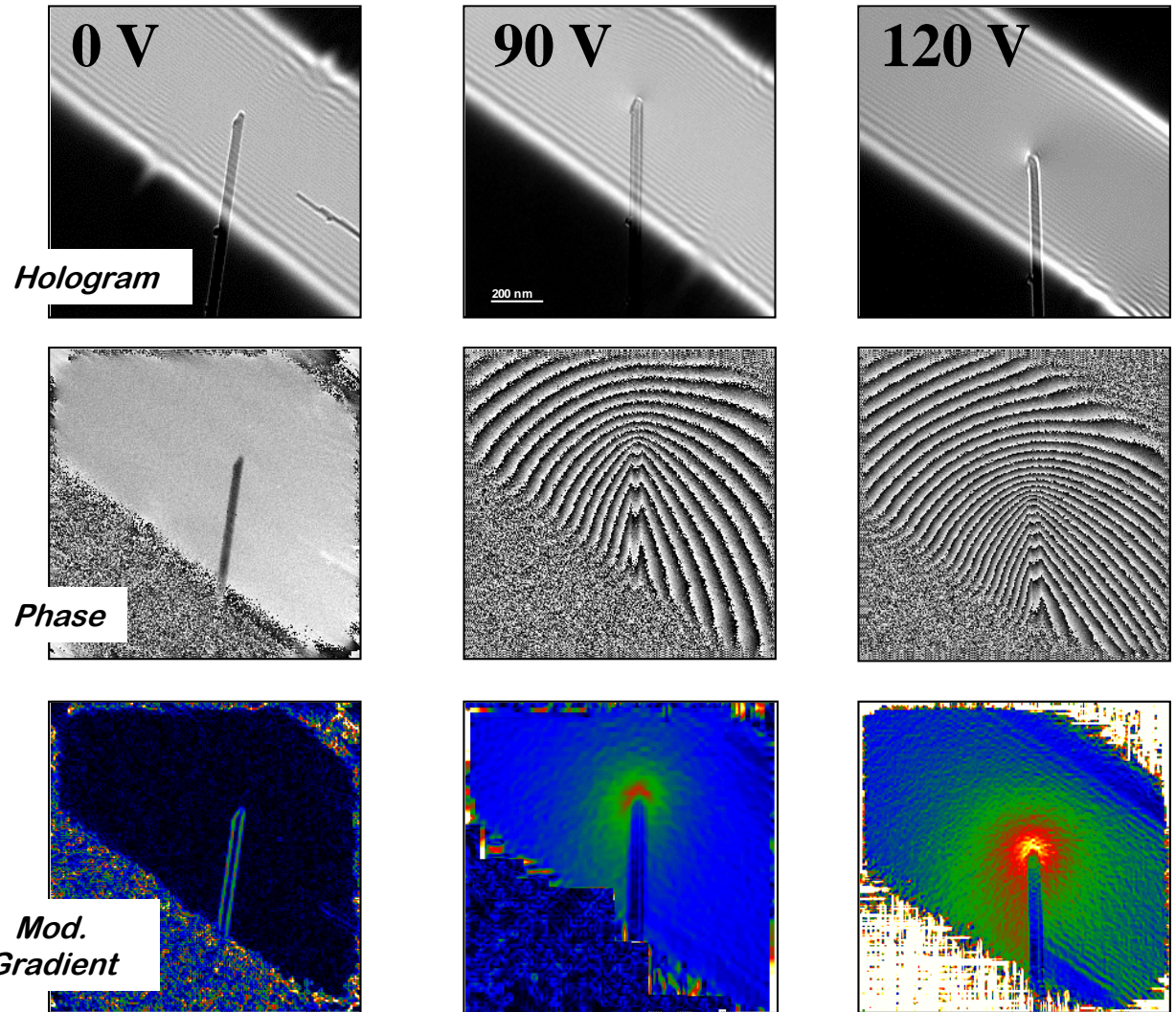


Dissociated mixed dislocation in GaN

What can you do with a TEM?

Electron
holography

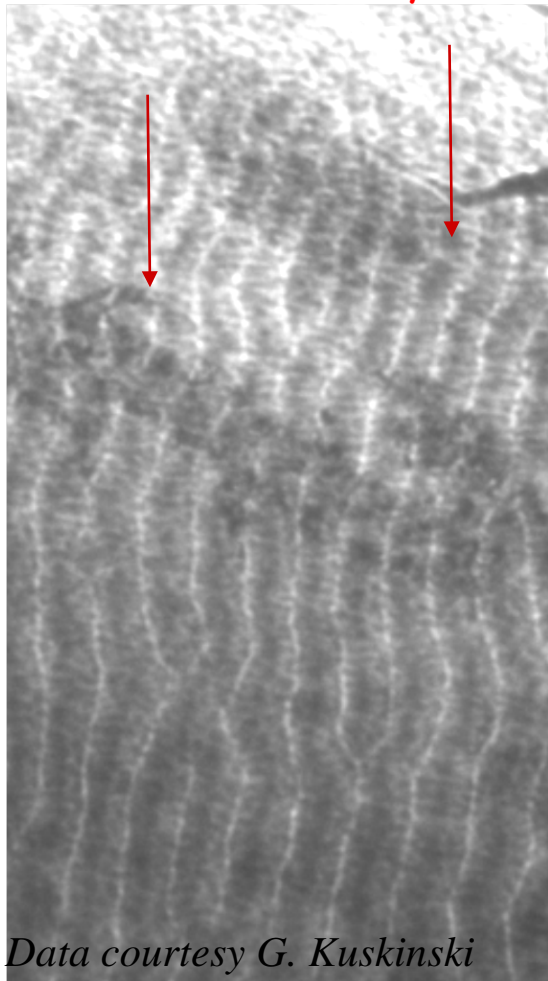
Map the
mean inner
potential of a
material



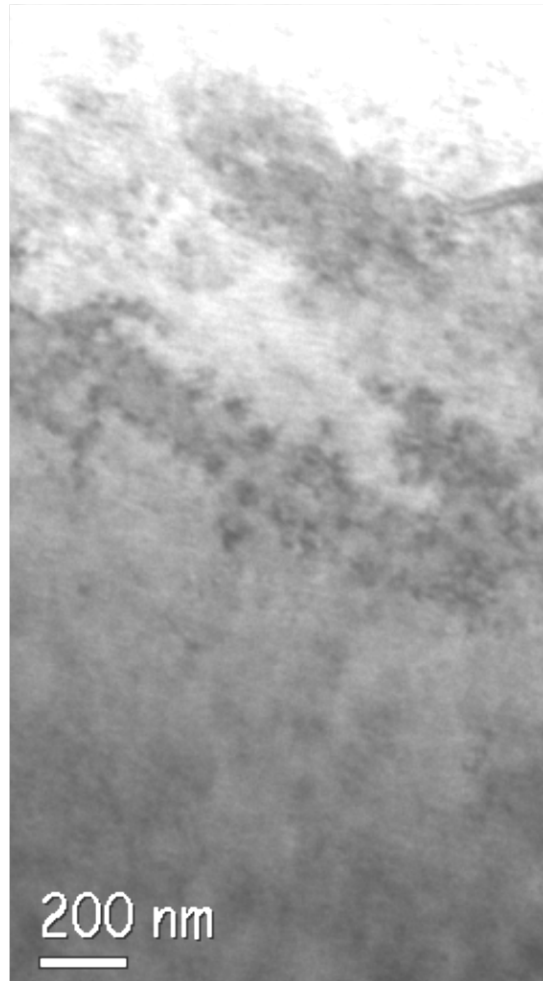
What can you do with a TEM?

“Lorentz” microscopy for imaging of magnetic structures

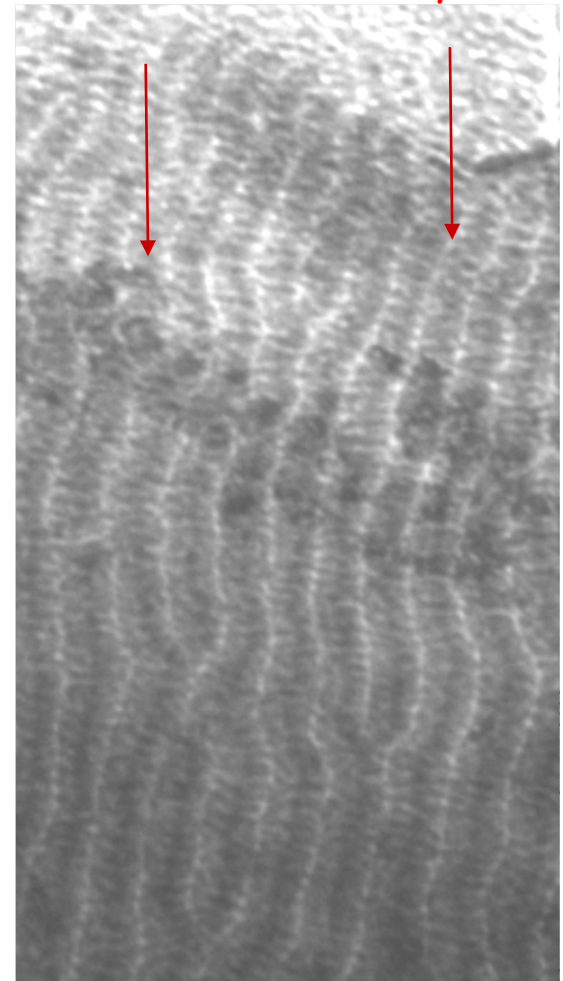
Defocus = $-15\mu\text{m}$



In focus



Defocus = $+15\mu\text{m}$

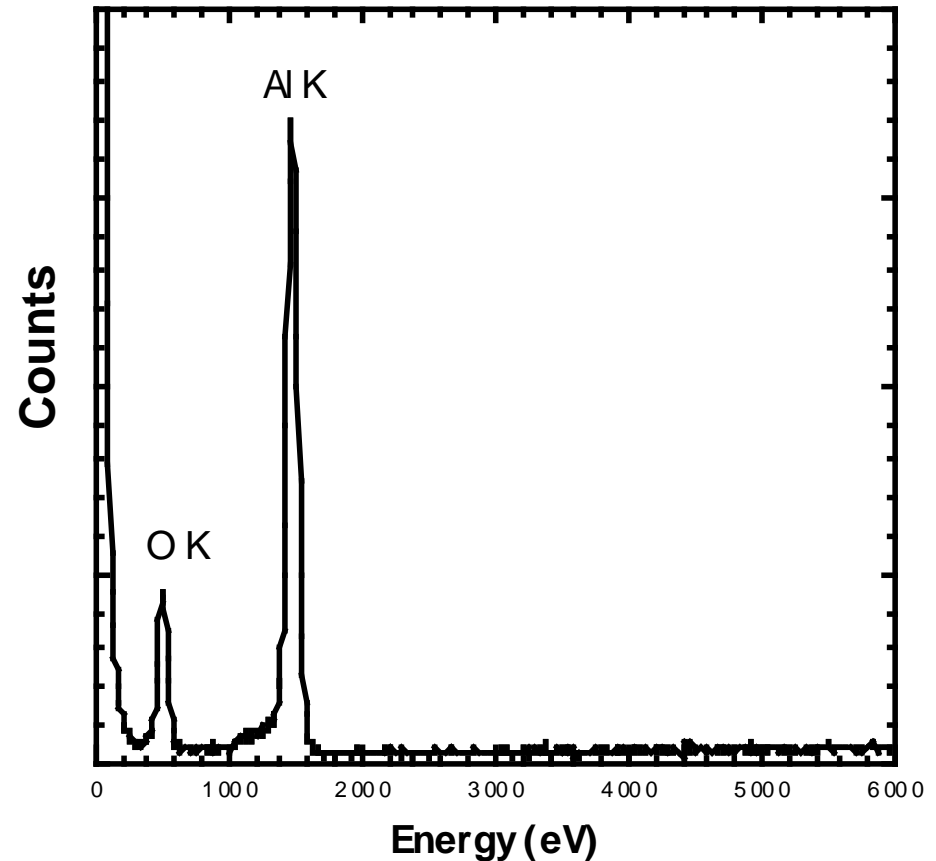


Data courtesy G. Kusinski

What can you do with a TEM?

Energy Dispersive X-ray Spectroscopy (EDS)

- Detection of characteristic x-rays excited by incident electrons.
- Spatial resolution on the order of probe size (can be as low as 2-3 Å)

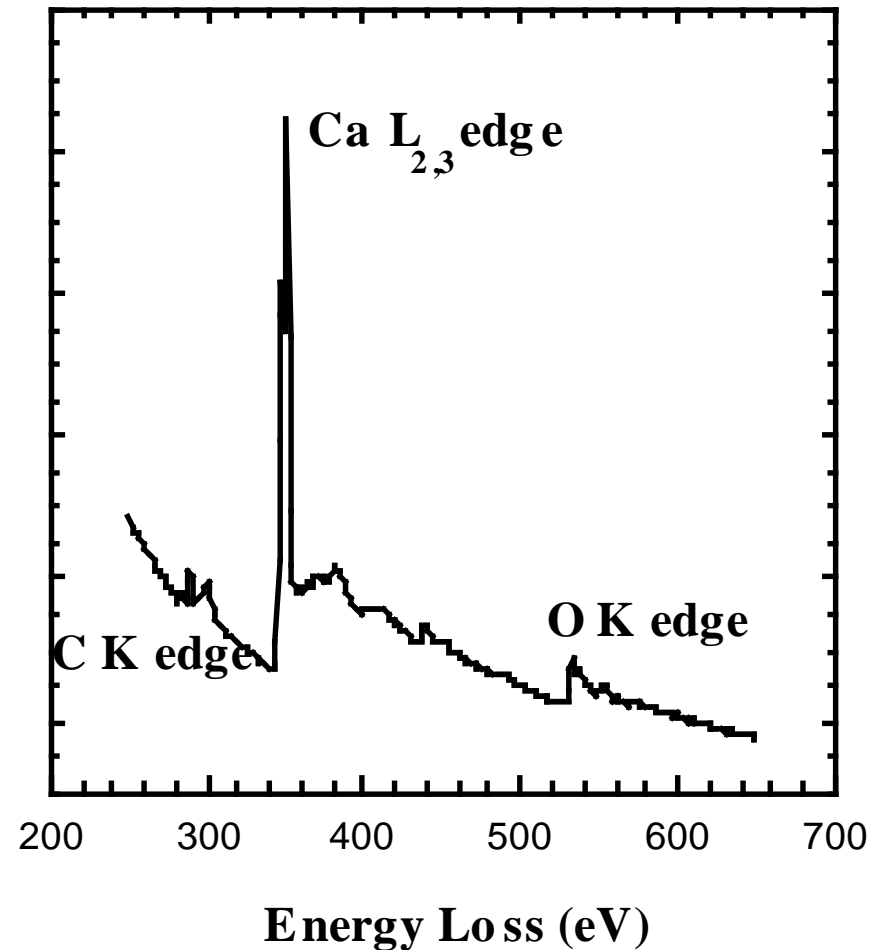


Simple EDS spectrum from Al_2O_3

What can you do with a TEM?

Electron energy loss spectroscopy

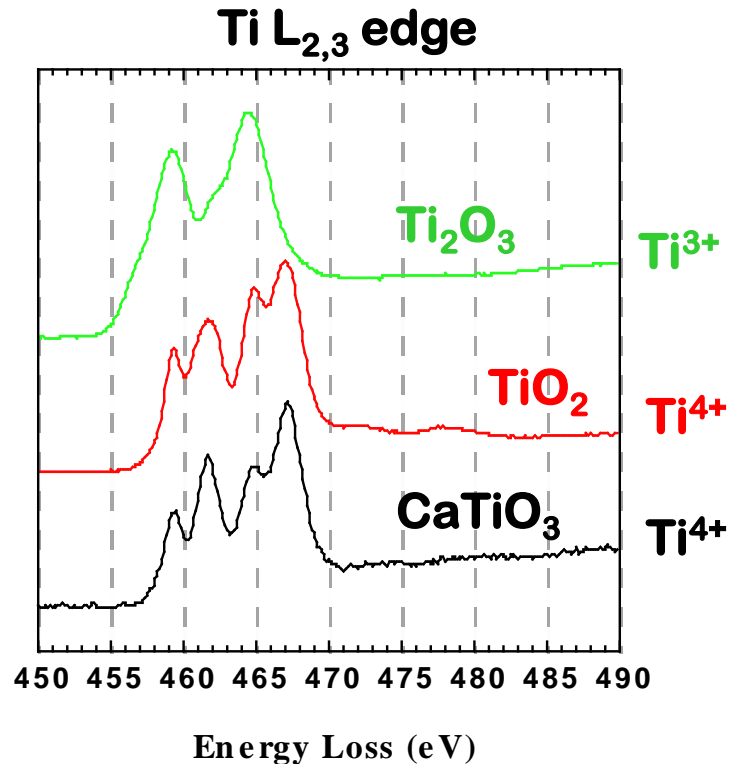
- Measures the amount of energy lost by the incident electrons.
- Similar spatial resolution, energy resolution of ≈ 1 eV.
- Probes density of state (DOS) locally.



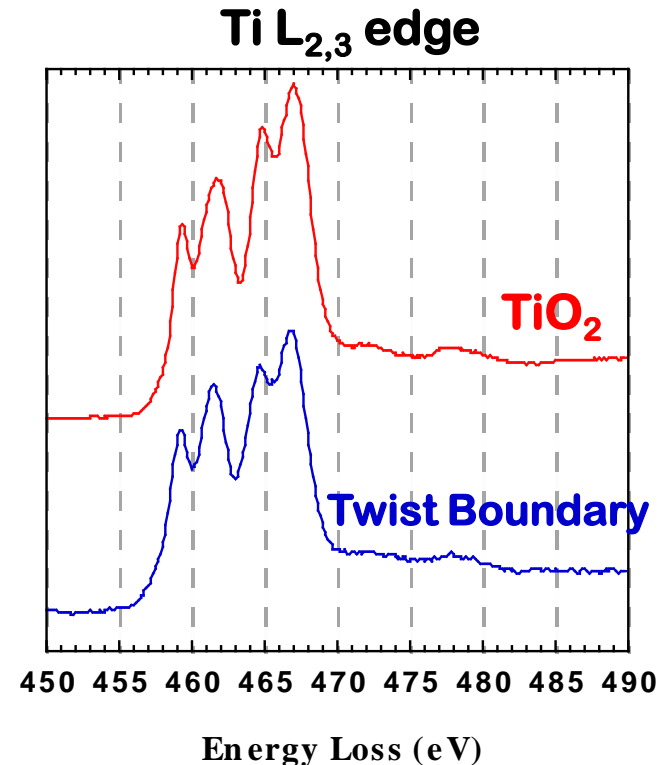
EELS spectrum from CaCO₃

What can you do with a TEM?

Ti valence determination using EELS



Ti L_{2,3} edge from trivalent Ti₂O₃ differs markedly from tetravalent compounds TiO₂ and CaTiO₃

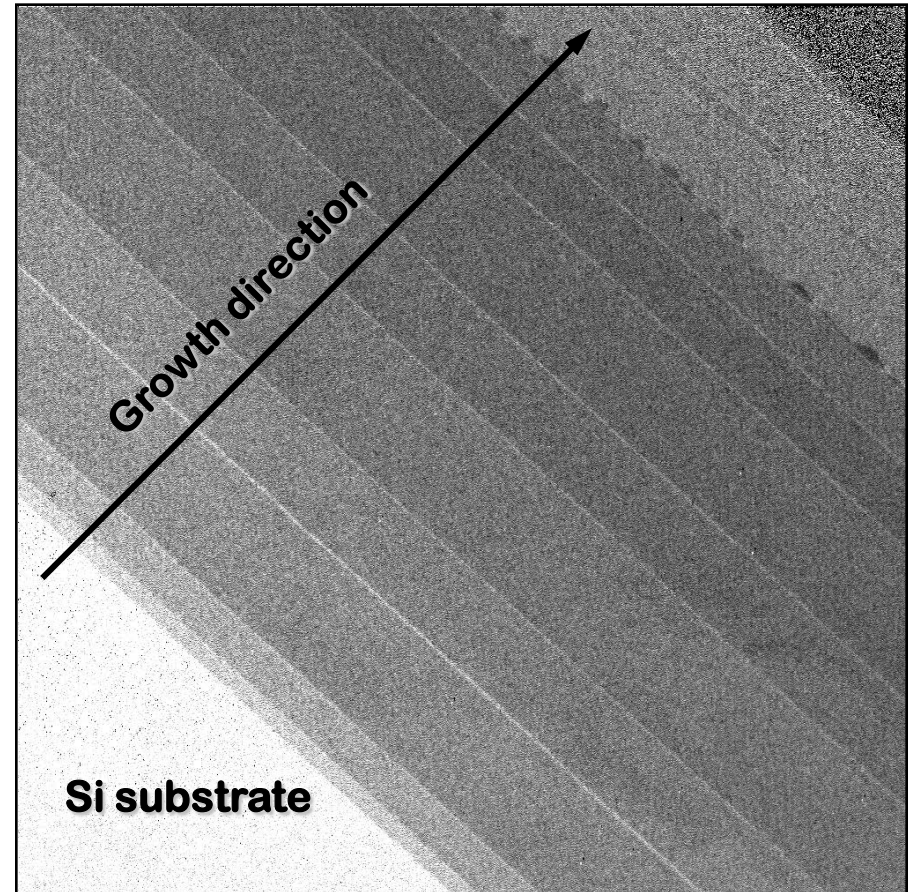


Ti L_{2,3} edge from twist boundary closely matches edge structure of TiO₂ standard (Ti⁴⁺).

What can you do with a TEM?

Energy Filtered Imaging

- Zero loss imaging removes inelastically scattered electrons from image
- Selective imaging of electrons that have lost a particular energy
- Most commonly used to create a map of local (≈ 1 nm) chemistry



Energy filtered image of a SiGe graded buffer structure using the Si K edge.

The brighter the pixel, the larger the concentration of Si.

What can you do with a TEM?

Dynamical behavior

- Possible to apply many type of stimuli to samples during simultaneous imaging.
- Probe interrelationships between structure / properties and processing
- Stimuli include:
 - Temperatures to 1300°C
 - Temperatures to LN₂
 - Chemical flux
 - Nanomanipulation
 - Nanoindentation
 - Electrical bias in combination with heating
 - Uniaxial strain



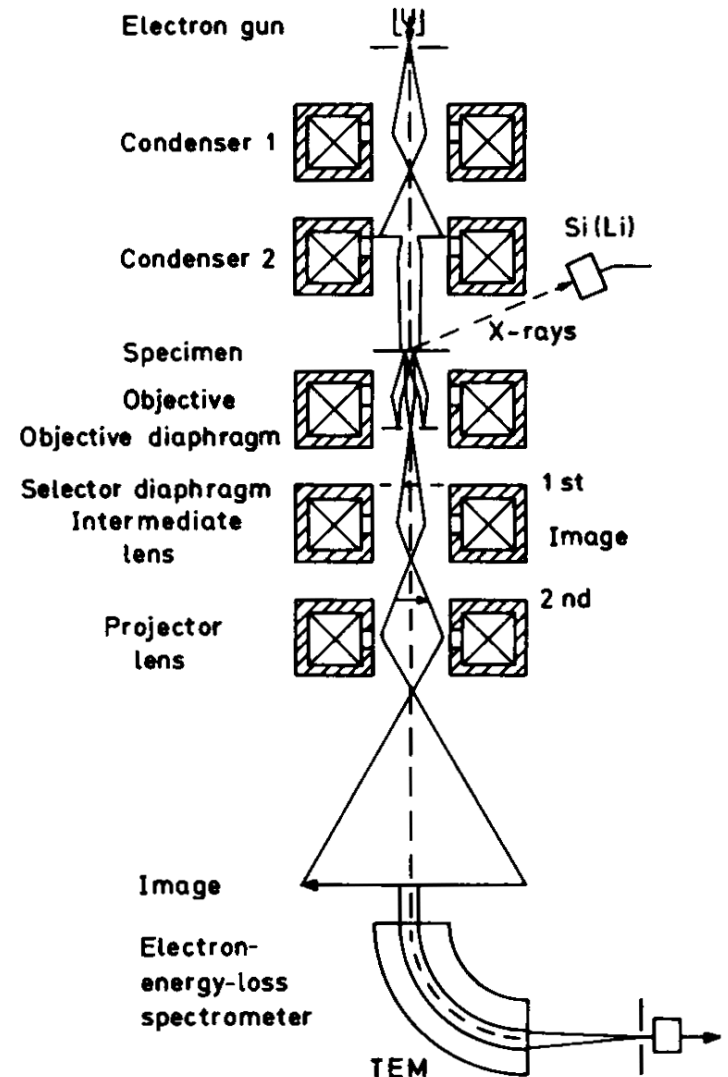
Interaction between threading and misfit dislocations in a SiGe heterostructure

A way to organize our thoughts

In MSE 582 we will learn how to “use” the microscope

We will discuss:

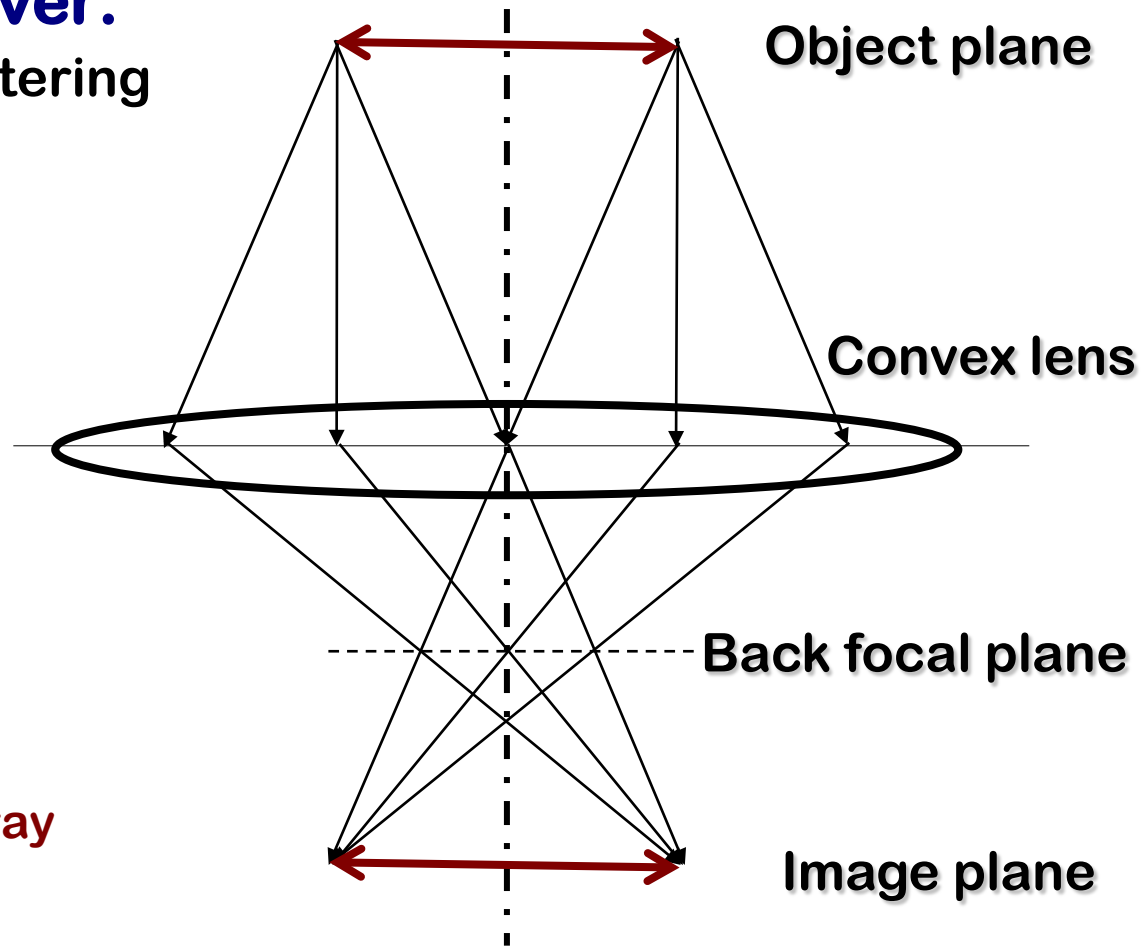
- Electrons & scattering, briefly
- Electron sources
- Lenses & aberrations
- How the instrument goes together
- Alignment
- The sample



A way to organize our thoughts

In MSE 640, we will cover:

- Elastic & inelastic scattering
- Diffraction
 - Single scattering (kinematical)
 - Multiple scattering (dynamical)
- Image formation
 - Diffraction contrast
 - Phase contrast
 - Incoherent imaging
- Spectroscopy
 - Energy Dispersive X-ray Spectroscopy
 - Electron Energy Loss Spectroscopy



Basic properties of electrons

a reminder ...